

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LIU ET AL.	
		Examiner BINH K. TIEU	Art Unit 2643	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,154,663 A	11-2000	Itamochi, Takeshi	455/569.2
*	B	US-6,272,359 B1	08-2001	Kivela et al.	455/567
*	C	US-6,594,366 B1	07-2003	Adams, Joel	381/74
*	D	US-5,943,627 A	08-1999	Kim et al.	455/569.1
*	E	US-5,963,872 A	10-1999	Stein, Per	455/557
*	F	US-4,882,745	11-1989	Silver, Alan H.	455/575.2
*	G	US-5,890,074 A	03-1999	Rydbeck et al.	455/558
*	H	US-6,351,629 B1	02-2002	Altschul et al.	455/90.1
*	I	US-6,195,570 B1	02-2001	Ishida, Takayasu	455/566
*	J	US-4,942,617	07-1990	Boylan, Mark	381/182
*	K	US-5,426,689 A	06-1995	Griffith et al.	455/575.2
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.